



XRF for Qualitative and Quantitative Materials Analysis

Who we are



Rigaku is the **global leader** in analytical X-ray solutions

SCX

XRD

XRF

CT

XRR

XRT

SAXS

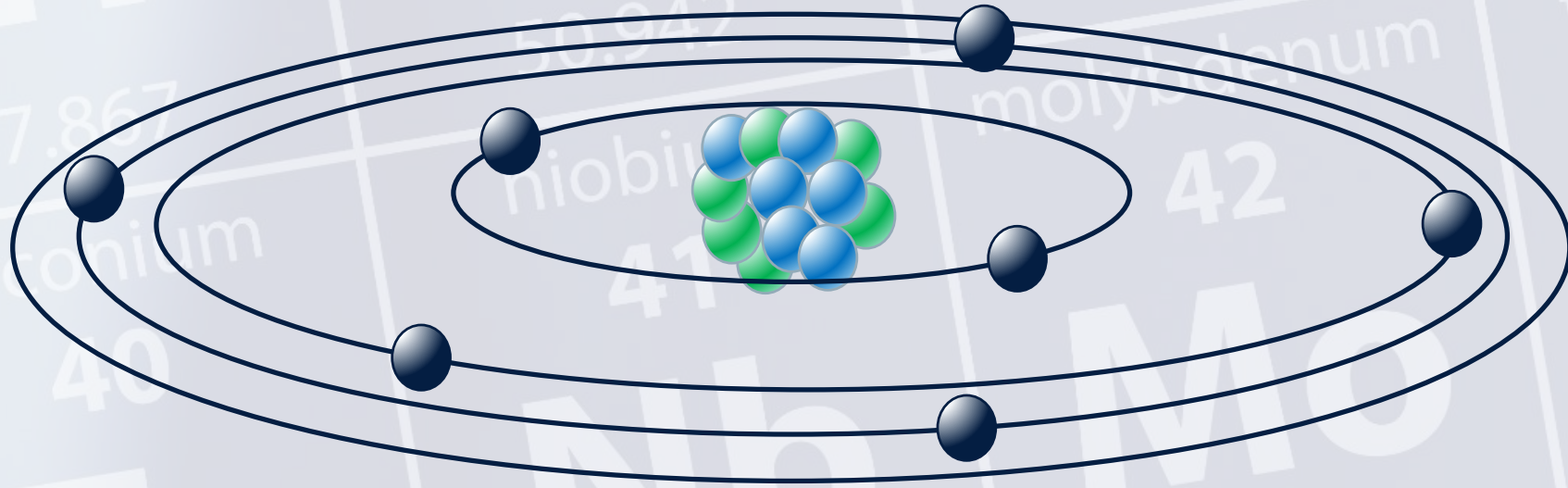


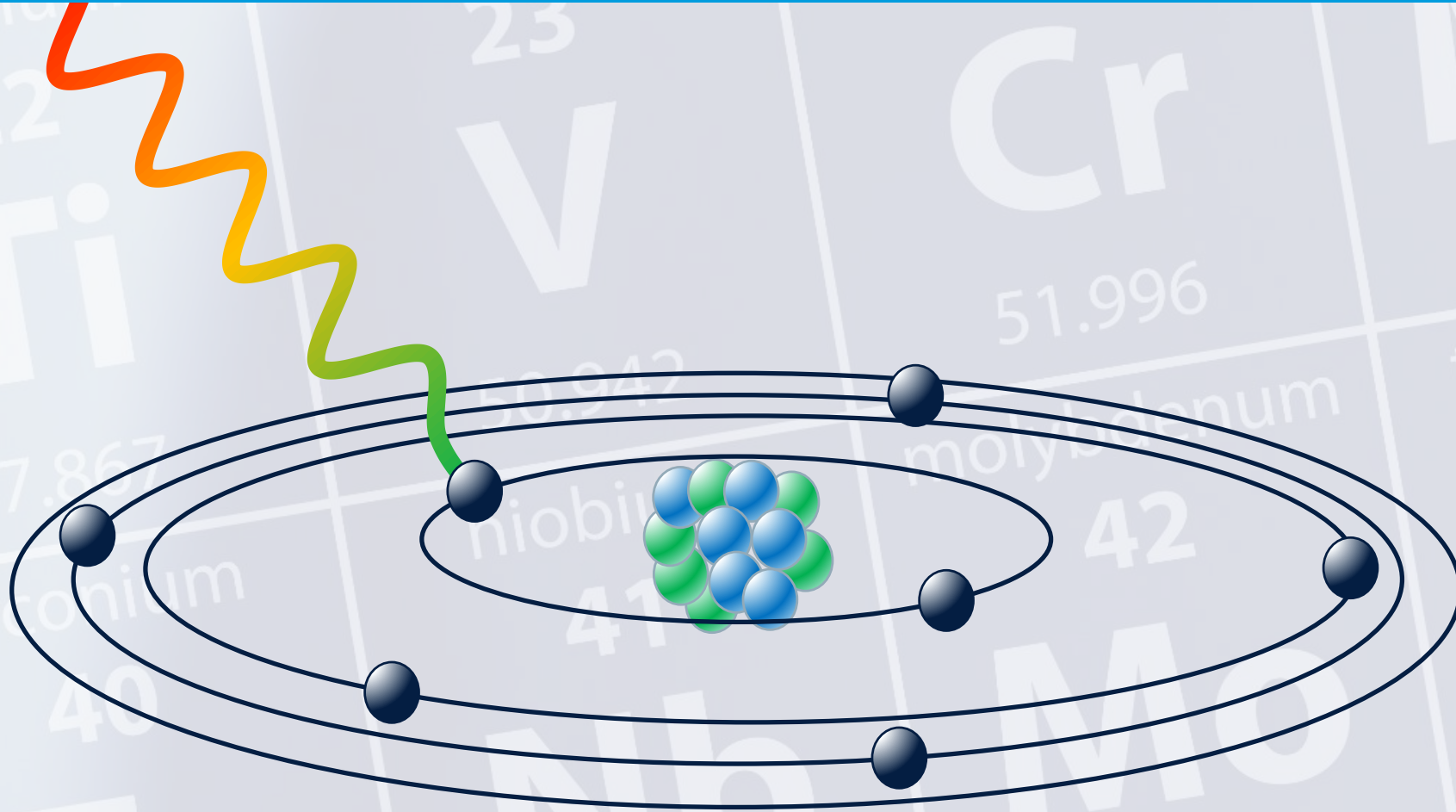
- Manufacturer of analytical X-ray instruments
- Partner to research institutes and industries
- High Quality craftsmanship **made in Japan**
- Leading Supplier of Scientific Instrumentation, 45 years
- Global Brands, Local Support
- Head Office & Laboratories – Stockport, UK

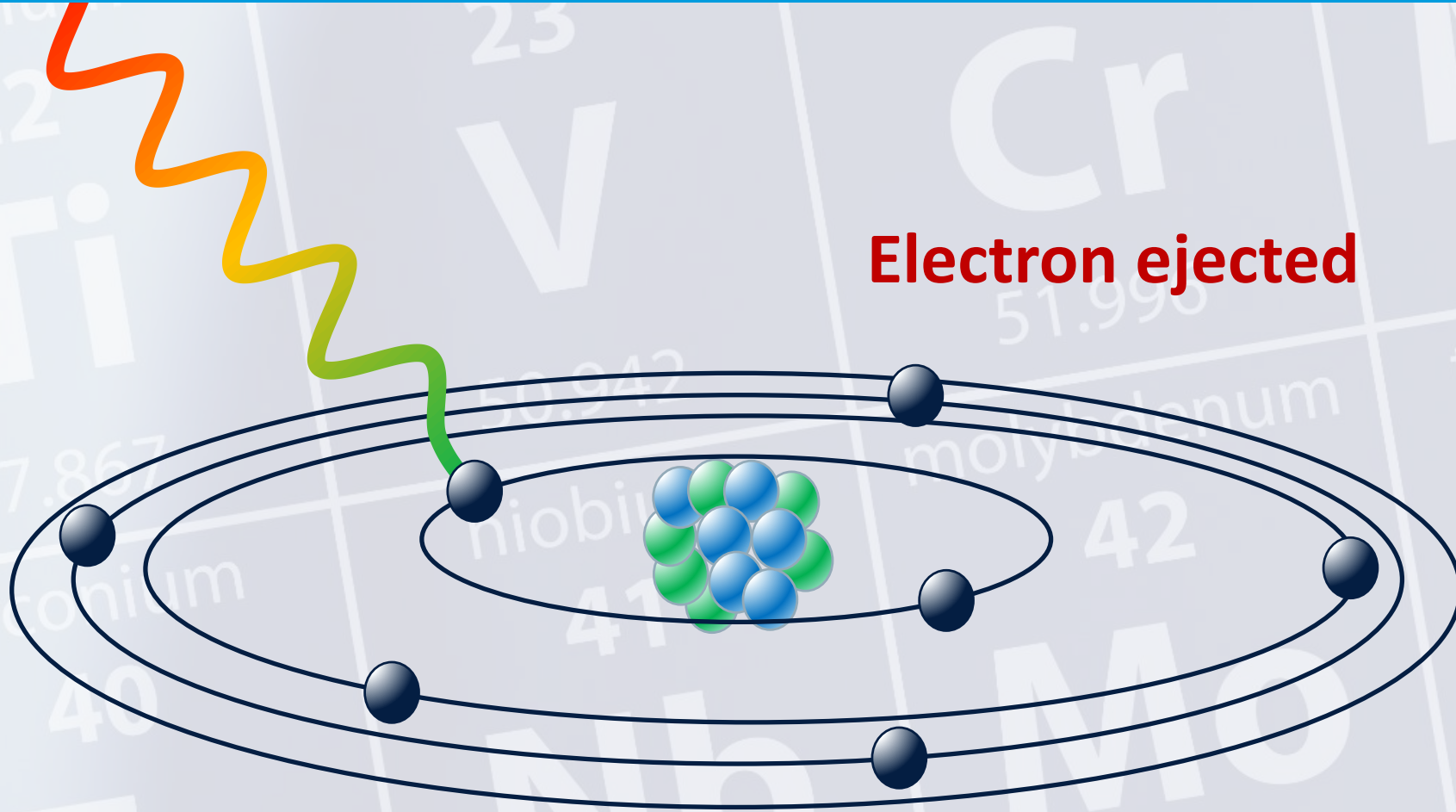


Rigaku
POWERING NEW PERSPECTIVES

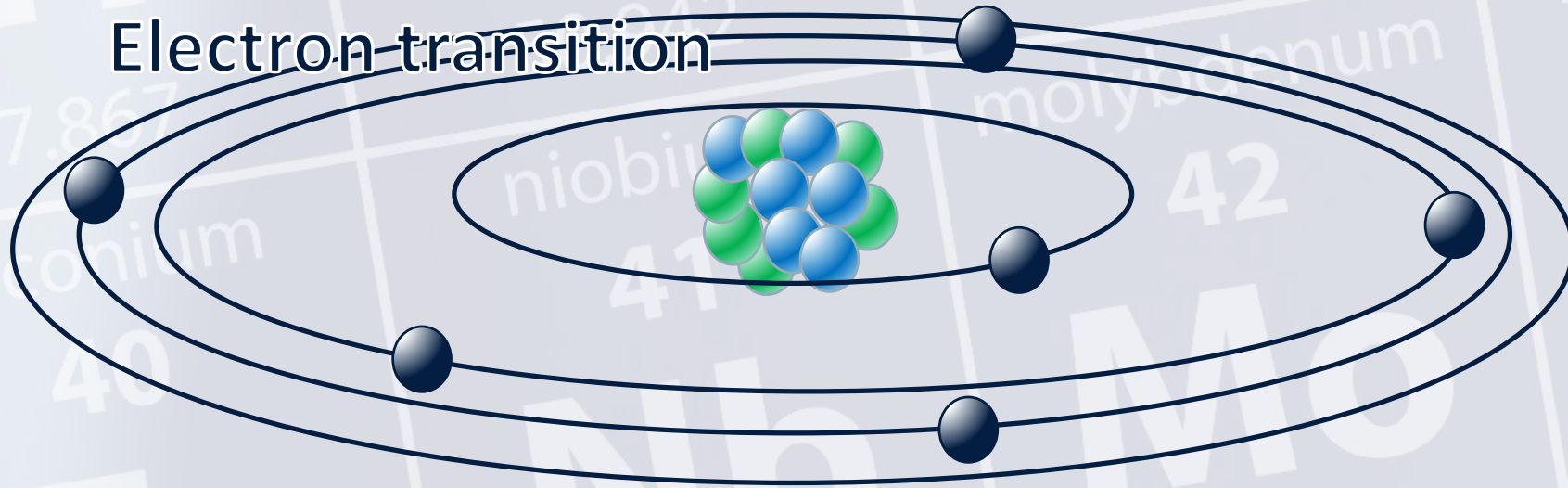
How does XRF work?

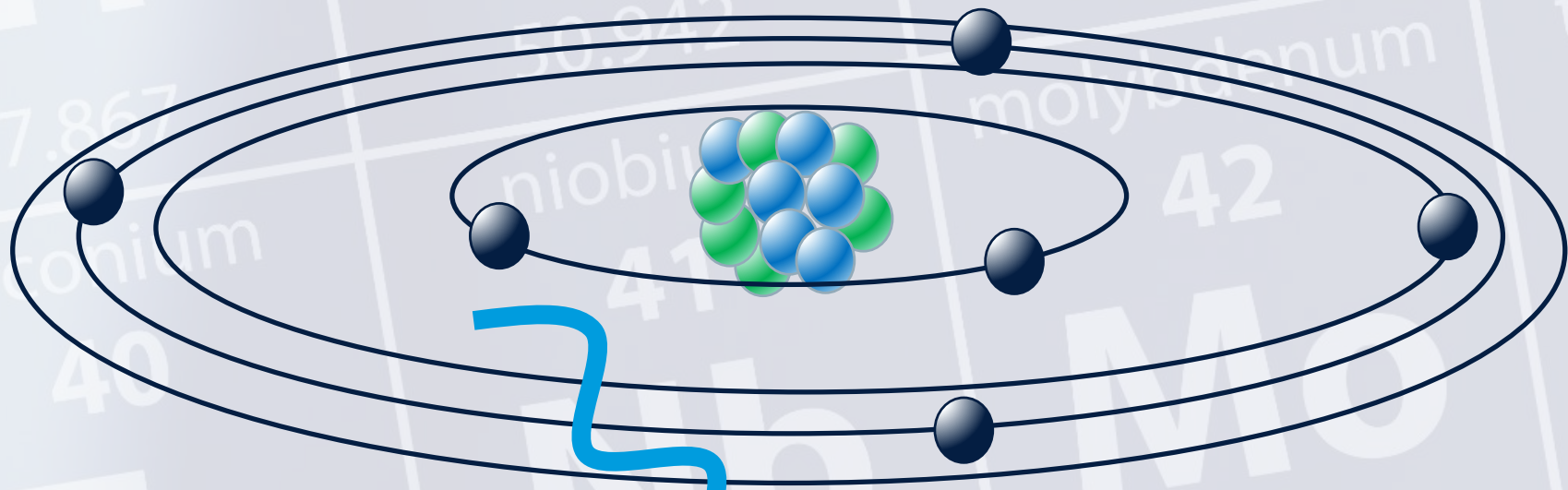




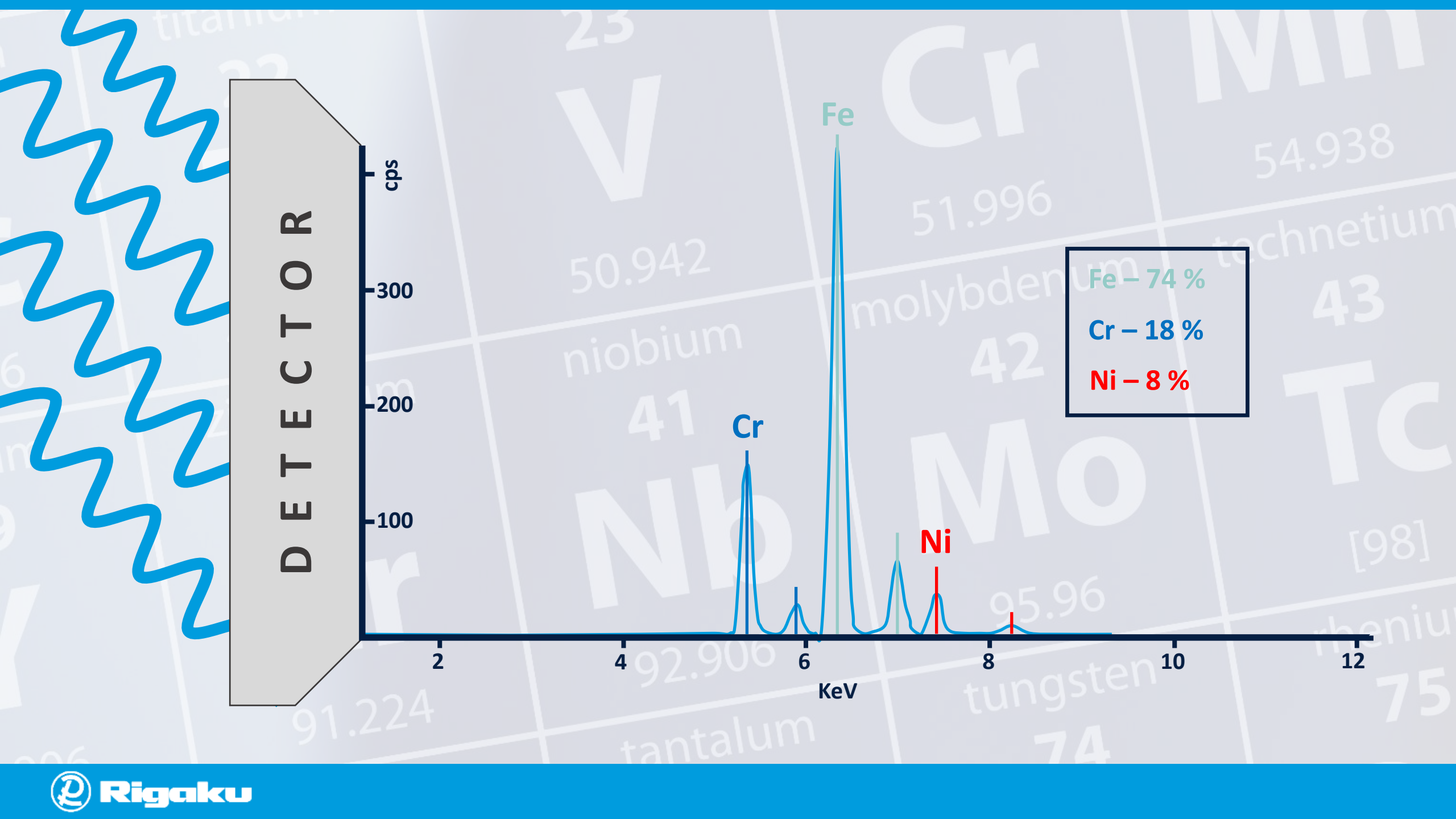


Electron transition



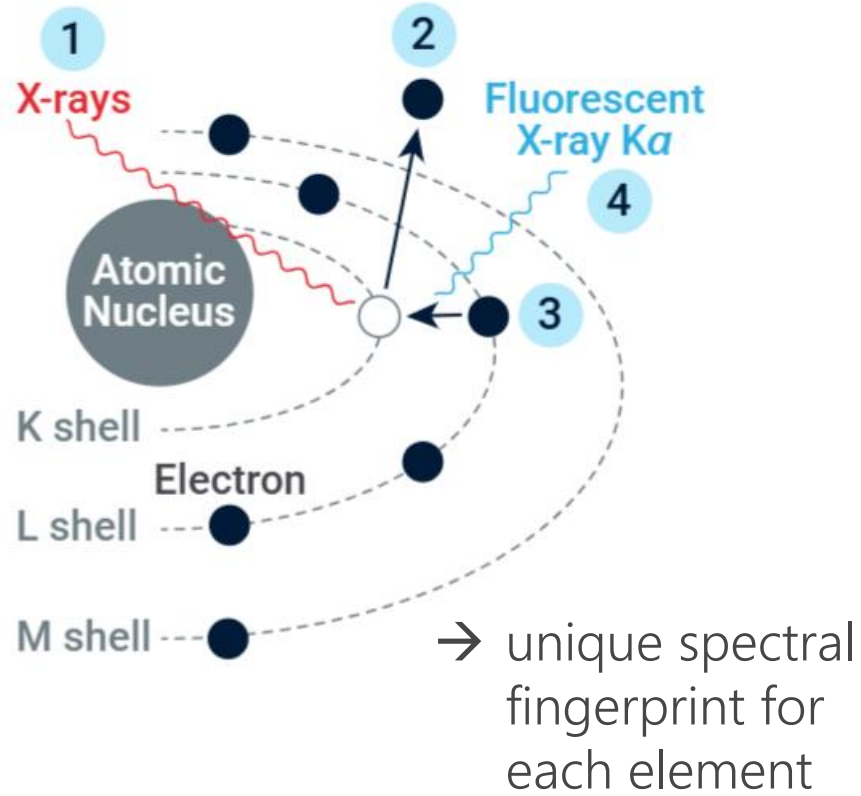


**Secondary X-Ray
(Characteristic)**

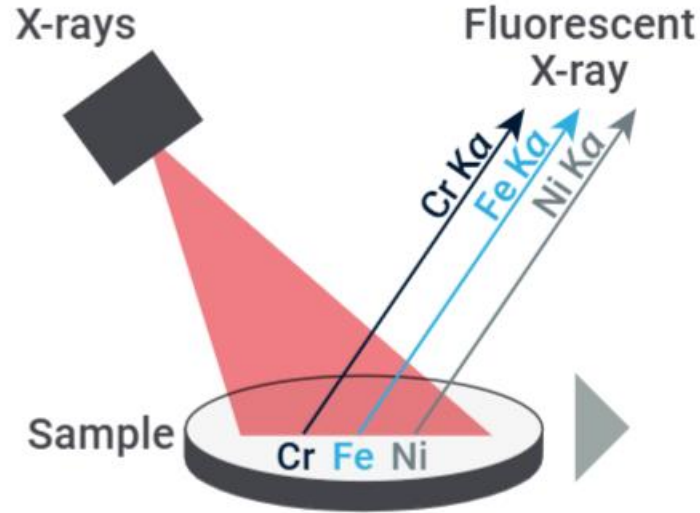


How does XRF work?

Principle

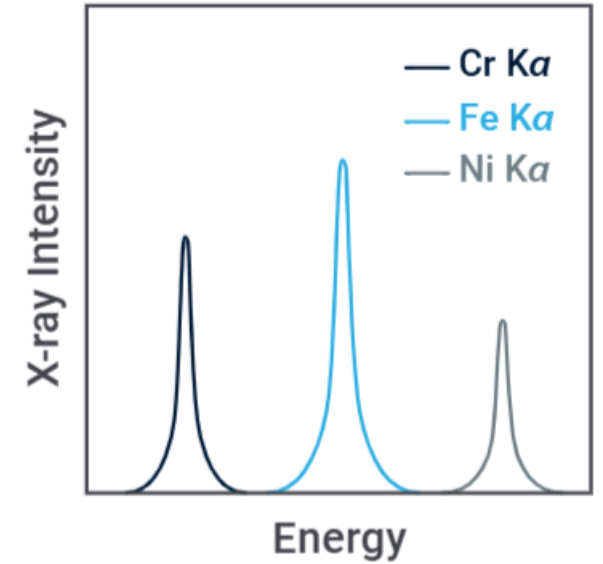


Qualitative Analysis



The elements in a sample can be identified from the energy or wavelength of the peak positions.

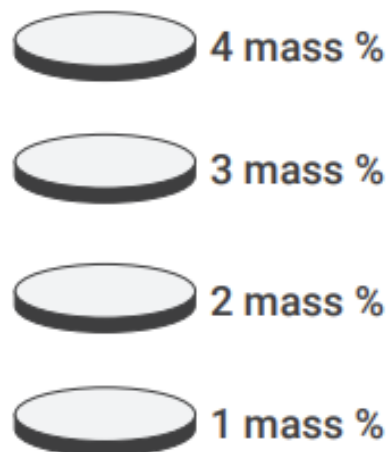
Quantitative Analysis



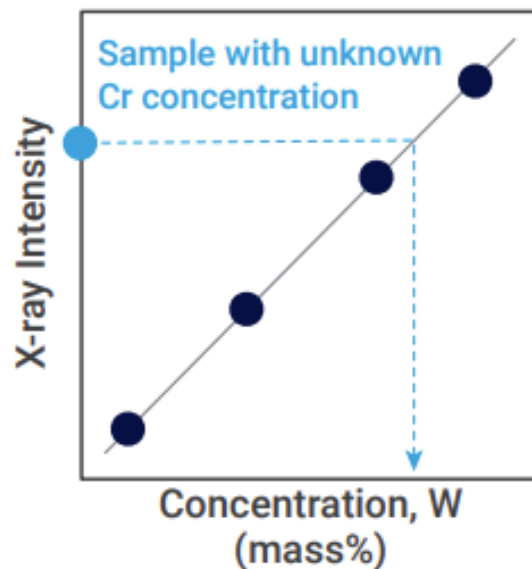
The elemental composition can be identified from the intensity of the signal at the peaks.

Calibration Curve

Cr Concentration

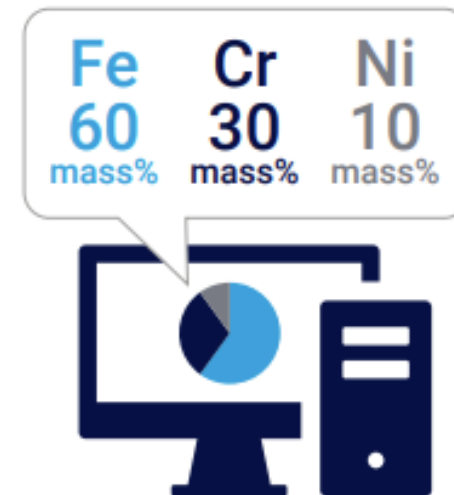
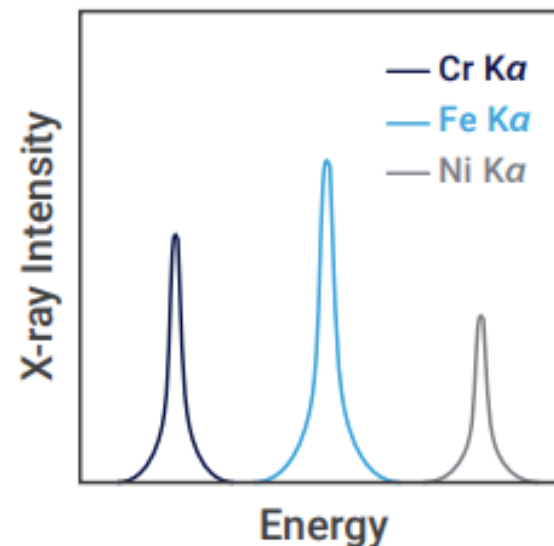


Calibration Curve



Dedicated calibration standards for the elements of interest in similar matrix are implemented as calibration curve for most accurate quantification of unknown samples.

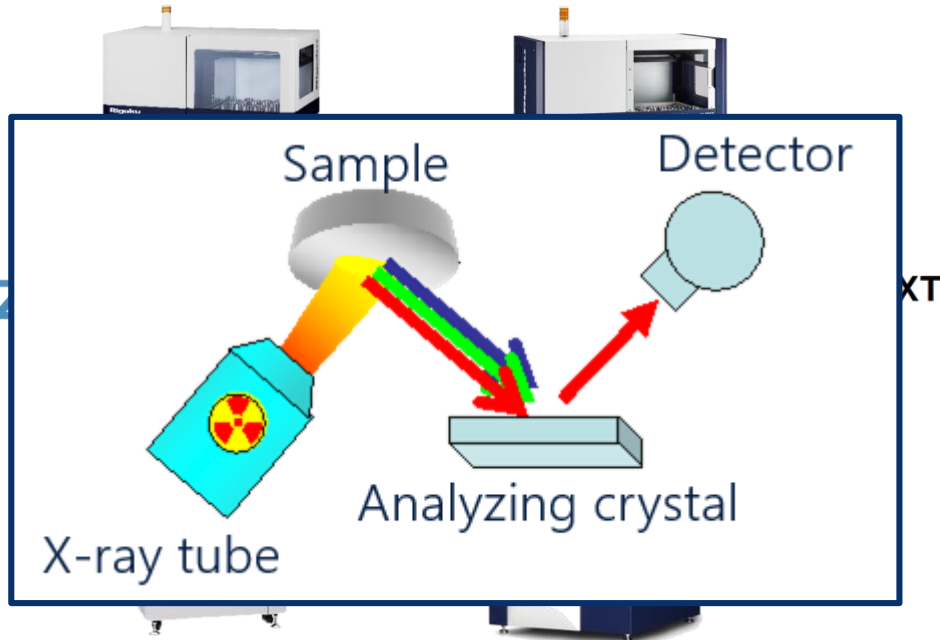
Fundamental Parameters (FP)



Fundamental parameters such as absorption coefficients and instrument specifications are used to calculate element concentrations without calibration standards.

Convenient for diverse samples & changing matrix.

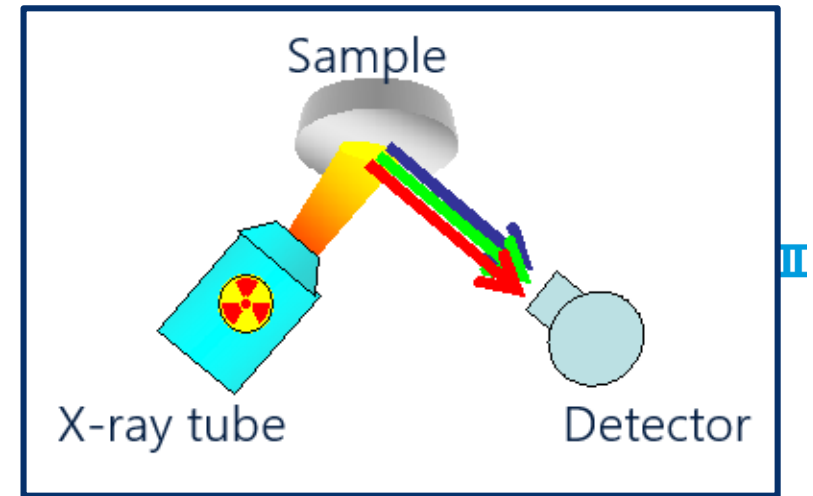
Wavelength dispersive (WD)



ZSX Primus IVi **Supermini200**

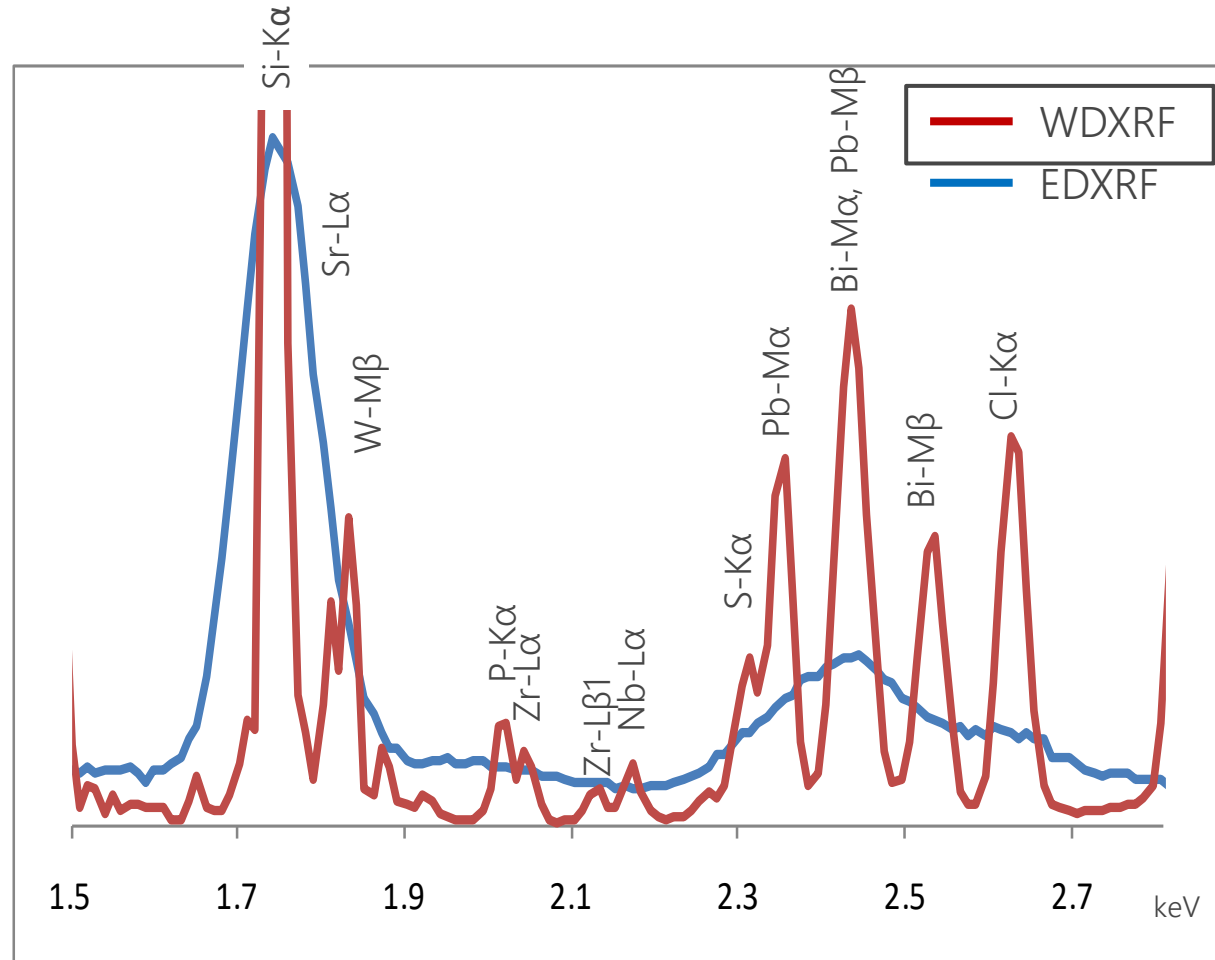
Excellent spectral resolution
(Less line overlaps)
High precision analysis

Energy dispersive (ED)



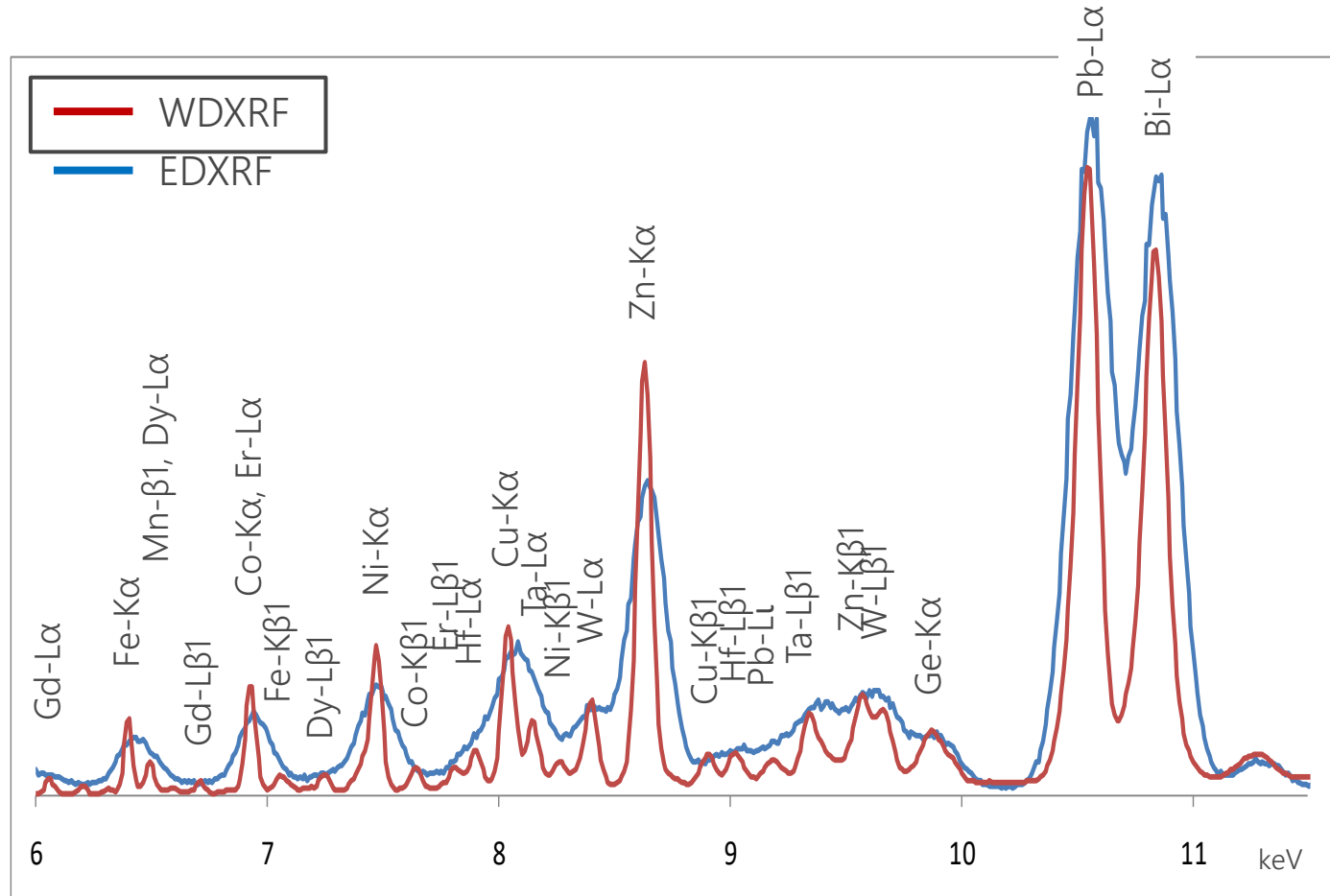
Suitable for screening analysis
Simple Operation
Fast analysis time

Light Element Range



Sample: glass

Heavy Element Range



Sample: glass

XRF the solution for a wide range of industries and applications

Semiconductor



Academic research



Metals



Petro



Cement



Battery



Pharma

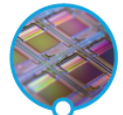


Rigaku Makes Smartphones Possible

Electronic Components

Processor (SoC) | Memory | Sensors | Display

Semiconductor



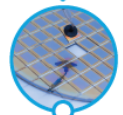
Wafer Processing

XRD Orientation analysis
XRT Quality assurance



Film Growth / Electrode Deposition

XRD Measurements of film thickness, lattice constants, and quality assurance
XRF Surface contamination analysis



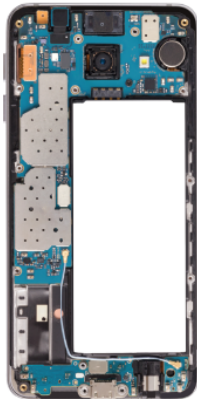
Dicing / Packaging

XRD Qualitative analysis and micro-area mapping



Printed Circuit Board (PCB)

CT Quality control



Glass

XRF Determination of the composition of raw materials, intermediates, and final glass products

CT Quality control



Battery

Mining Raw Materials

XRD | XRF
Monitoring composition

Refining

XRD | XRF
Quality assurance

Battery Cell

CT
Quality control and life-cycle



Casing

Plastics



Petrochemical Industry

XRF
Analyzing raw materials



Production of Polymers

XRF
Checking quality and remaining impurities



XRD
Phase identification and quantification

Metal



Mining

CT
Exploration of ores and determination of the phases of critical raw materials

XRD | XRF
Determination of the composition of ores



Metal Production

XRD
Identifying phases in metals and alloys, residual stress analysis, determining crystallite size and texture, and quality control of coatings and texture

XRF
Monitoring composition of intermediate products, verifying the composition of alloys and inspecting end products

CT
Quality control



Rigaku

POWERING NEW PERSPECTIVES

MINING

RECYCLING

**XRF for
Batteries**

**REFINING:
Cathode**

**REFINING:
Anode**

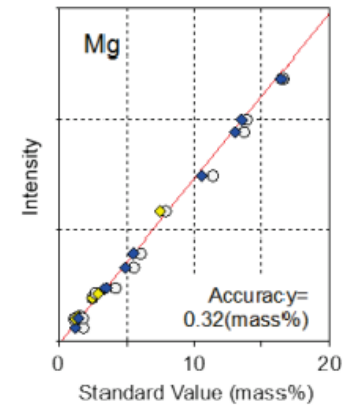
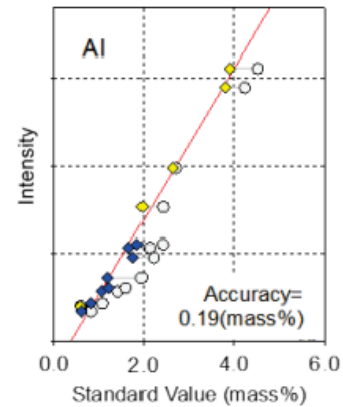
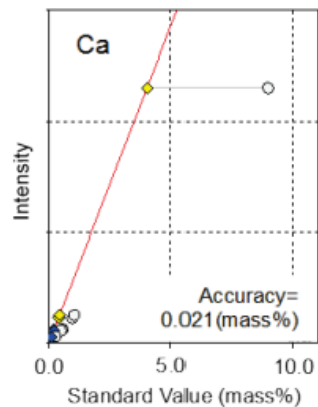
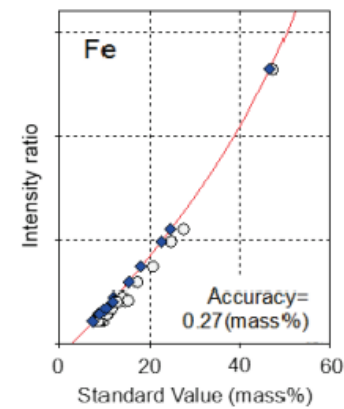
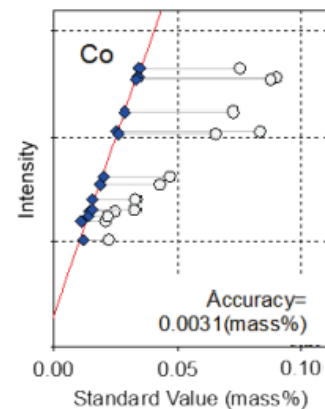
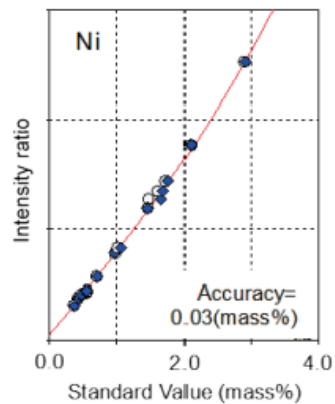


MINING



Rigaku
POWERING NEW PERSPECTIVES

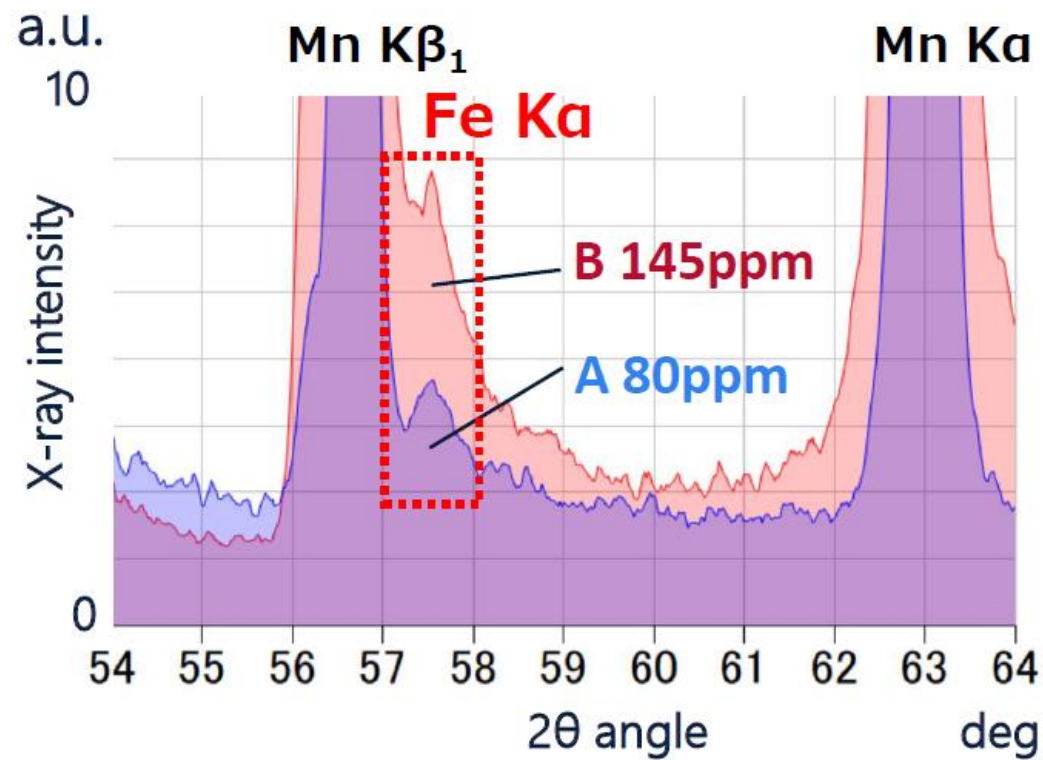
SUPERMINI 200



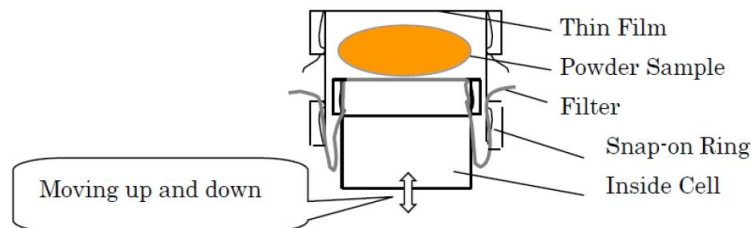
REFINING: Cathode



PRIMUS IV



REFINING: Anode



Graphite powder



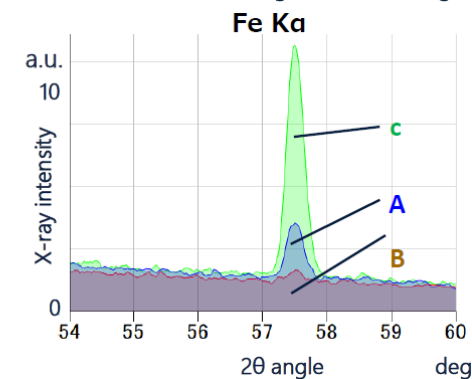
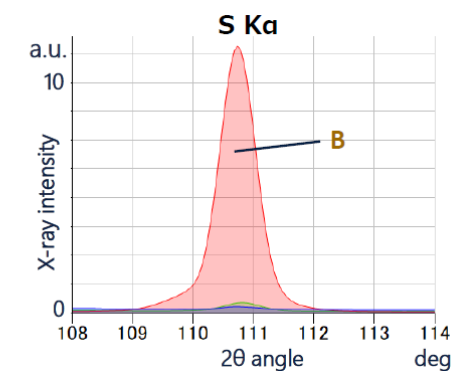
SQX analysis result of impurities

Unit: ppm

Sample	Na	Mg	Al	S	Ca	Fe	Zr
A	83	249	28	38	73	39	13
B	N.D.	975	24	2958	41	6	N.D.
C	81	242	42	76	81	180	4

* N.D.: under detection limit

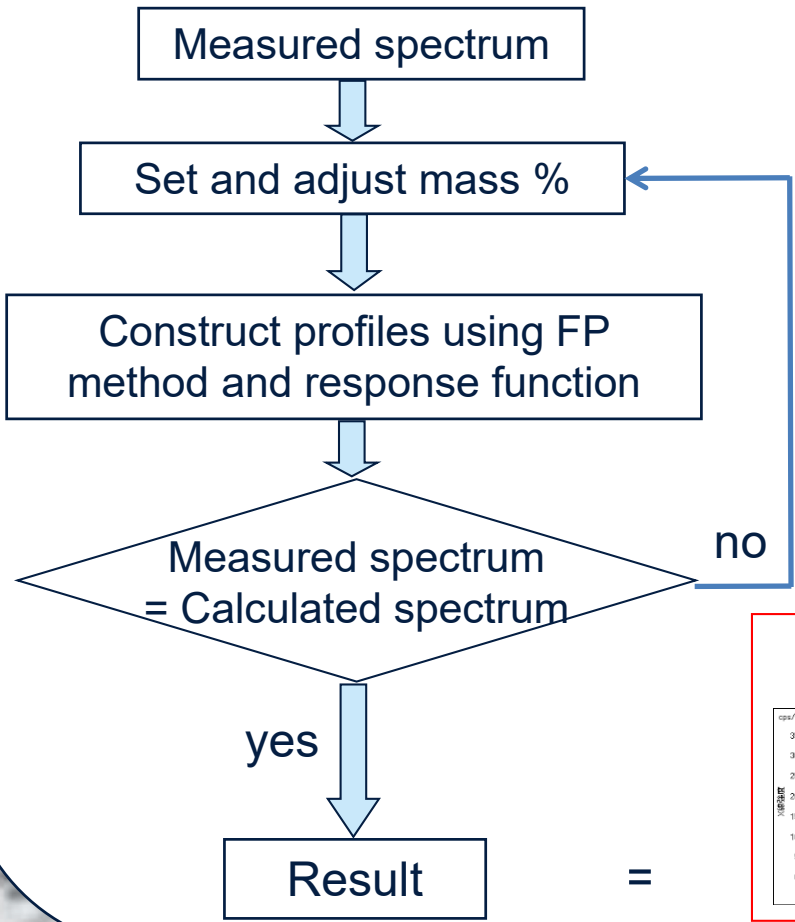
- ◆ Impurities in graphite samples were detected with high accuracy.
- ◆ High concentration of S and Fe impurities were detected in sample B and sample C, respectively. The difference in impurity levels depends on the sample grade.



RECYCLING

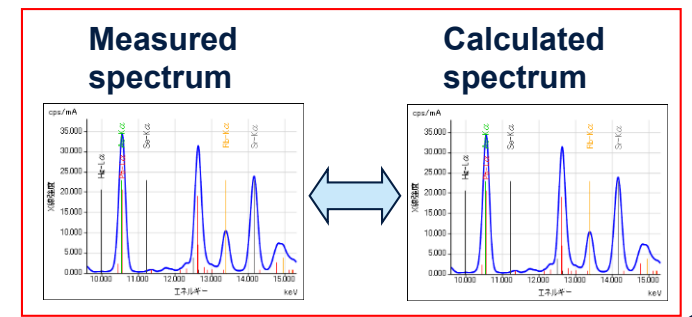


RIGAKU SQX FP



XRF vs ICP: Black Mass

		Ni	Co	Al	Cu
A	ICP	6.36	31.3	15.2	8.68
	XRF	6.45	31.0	12.1	7.34
B	ICP	17.2	17.7	8.46	4.41
	XRF	19.7	20.3	7.69	4.83
C	ICP	26.9	18.8	14.5	2.54
	XRF	26.0	20.8	14.7	2.50



Rigaku's WDXRF Instruments

Sequential

Simultaneous



Supermini200

- Optimized as a benchtop WDXRF
- Best Light element
- Best for the determination of Cl, no spectral overlap



ZSX Primus III ^{NEXT}

- Optimized for solids
- Standard system
- Normal sample throughput



ZSX Primus IV

- Optimized for powder samples
- Standard system
- High sample throughput



ZSX Primus IV_i

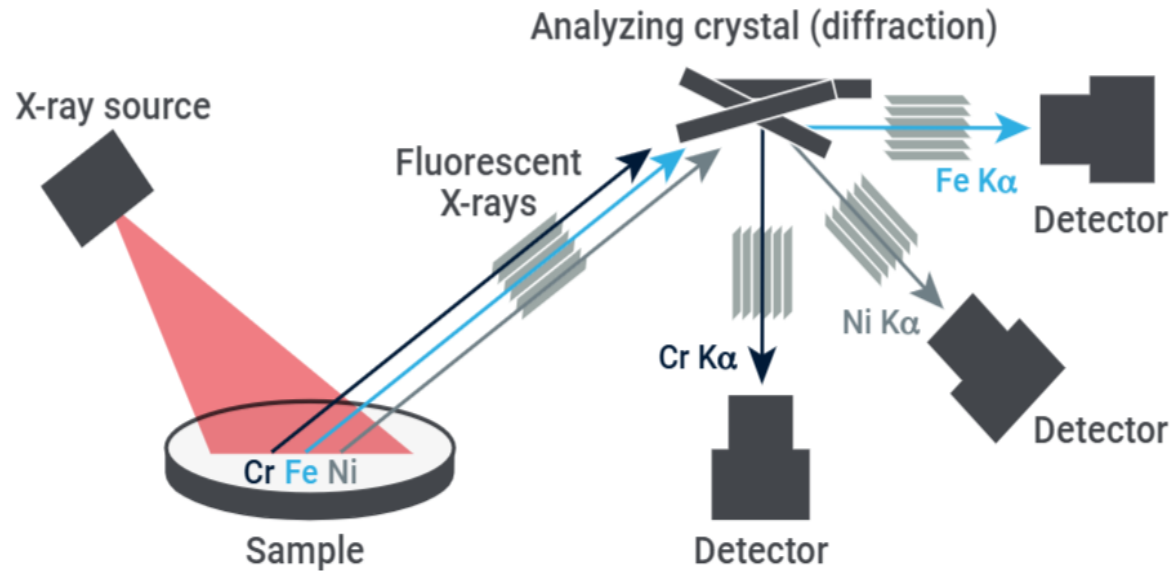
- Optimized for liquid samples
- Small Footprint
- Normal to high sample throughput



Simultix 15

- Optimized for high speed
- Most powerful system
- High sample throughput

Instrumental Set-Up – Advanced Analysis



Tube-above geometry allows for thinner tube window and hence gives higher intensities for detection of trace elements & fast measurements.

optimize selection of analyzer crystals for elements to be detected



Analyzing crystal	Atomic number									
	1	10	20	30	40	50	60	70	80	90
LiF (200)			^{19}K				^{60}Nd			
PET*1		^{13}Al	^{21}Sc					^{49}In		^{96}Cm
Ge*2		^{15}P	^{21}Sc						^{70}Yb	^{77}Ir
RX26*3		^8O	^{16}S					^{40}Zr	^{48}Cd	^{78}Pt ^{83}Bi
LiF (220)			^{24}Cr				^{34}Se			
LiF (420)			^{24}Cr					^{60}Nd		^{96}Cm
RX4			^{30}Zn					^{58}Ce		^{96}Cm
RX9								^{60}Nd		^{96}Cm
RX35		^{14}Si								
RX40		^{15}P	^{17}Cl							
RX45		^8O	^{12}Mg							
RX61		^7N	^8O							
RX61F		^7N								
RX75		^5B	^6C							
RX85*4		^6C								
		^4Be	^5B							
		^4Be	^5B							

— K line
— L line
— M line

Send in your samples

XRF feasibility demonstration



Qualitative and (semi-) quantitative measurements of your samples

XRF Demonstrations

XRF demonstrations or 3 days application training in our lab



Hardware and software training including method development

XRF Training

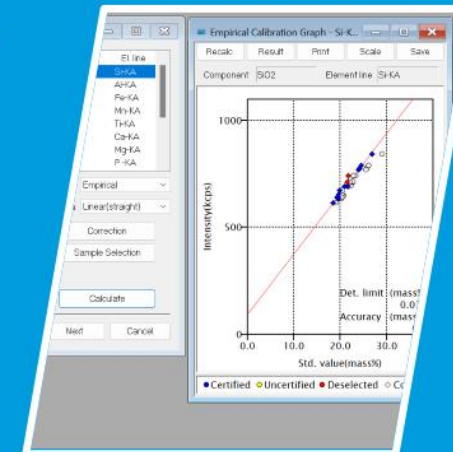
2-4 days application training at your facilities



Hardware and software training including method development

After-care Support

Remote support via Phone, TeamViewer or MS Teams



Advising on software, hardware and application solutions



Mission Statement



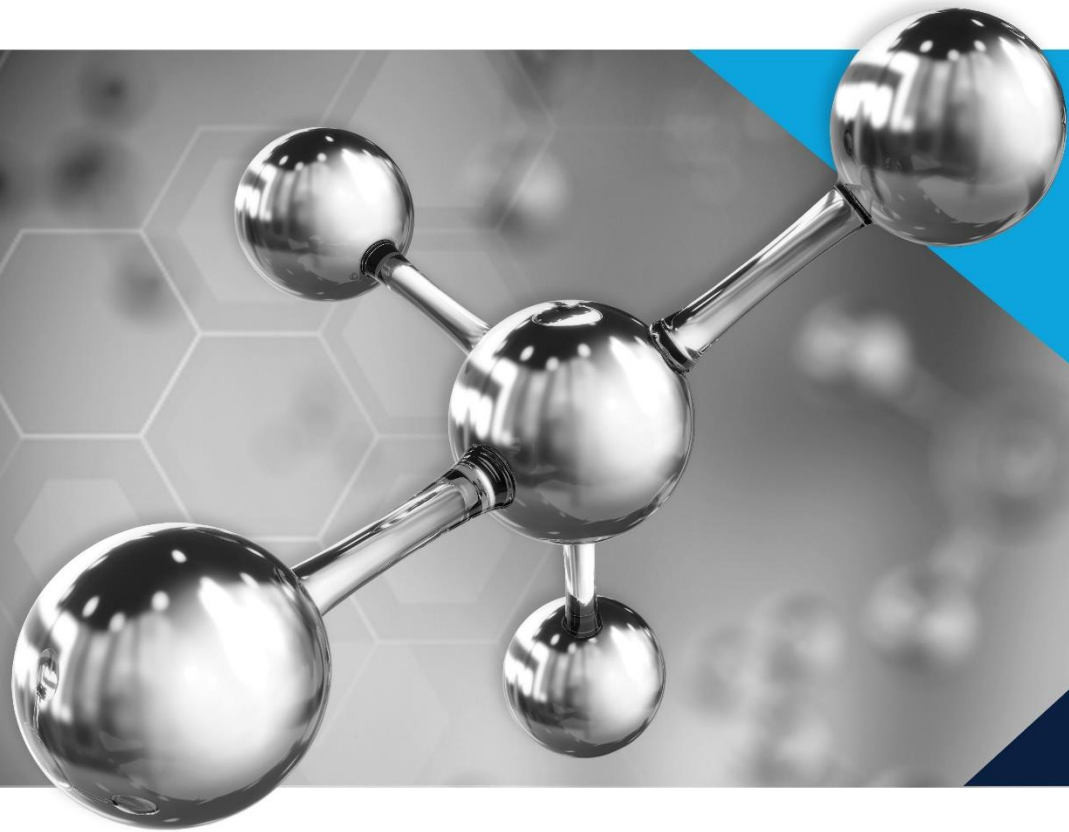
In everything we do at Rigaku, we believe in advancing humanity through **science** and **technology**



We do this by making our instruments exceptionally **engineered**, **user-friendly** and we offer the **best service**



Thus, Rigaku has grown from a manufacturer of X-ray instruments into a leading provider of **analytical X-ray solutions for material analysis**



Questions?